Test Report

No. : KA/2020/60957R1 Date : 2020/06/23

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

The following sample(s) was/were submitted and identified by/on behalf of the applicant as :

Sample Submitted By	:	NXP SEMICONDUCTORS
Sample Description	:	NXP WAFERS 2020
Style/Item No.	:	SSMC-200mm
Sample Receiving Date	:	2020/06/12
Testing Period	:	2020/06/12 to 2020/06/19

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Test Requested : (1) As specified by client, with reference to RoHS 2011/65/EU Annex II and amending Directive (EU) 2015/863 to determine Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP contents in the submitted sample(s).
(2) Please refer to next pages for the other item(s).

Test Result(s) : Please refer to next page(s).

Conclusion : (1) Based on the performed tests on submitted sample(s), the test results of Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP comply with the limits as set by RoHS Directive (EU) 2015/863 amending Annex II to Directive 2011/65/EU.

Ray Chang Ph.D. / Manager - [illegible]
Signed for and on behalf of
SGS Taiwan Limited
Chemical Laboratory-Kaohsiung

SGS TAIWAN LTD. TAIWAN

CHECK REPORT
PIN CODE: 1C5CA604

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Test Result(s)

PART NAME NO.1 : MULTICOLORED WAFER

Test Item (s)	Unit	Method	MDL	Result	Limit
				No.1	
Cadmium (Cd)	mg/kg	With reference to IEC 62321-5: 2013 and performed by ICP-OES.	2	n.d.	100
Lead (Pb)	mg/kg	With reference to IEC 62321-5: 2013 and performed by ICP-OES.	2	n.d.	1000
Mercury (Hg)	mg/kg	With reference to IEC 62321-4:2013+ AMD1:2017 and performed by ICP-OES.	2	n.d.	1000
Hexavalent Chromium Cr(VI)	mg/kg	With reference to IEC 62321-7-2:2017 and performed by UV-VIS.	8	n.d.	1000
Sum of PBBs	mg/kg	With reference to IEC 62321-6:2015 and performed by GC/MS.	-	n.d.	1000
Monobromobiphenyl	mg/kg		5	n.d.	-
Dibromobiphenyl	mg/kg		5	n.d.	-
Tribromobiphenyl	mg/kg		5	n.d.	-
Tetrabromobiphenyl	mg/kg		5	n.d.	-
Pentabromobiphenyl	mg/kg		5	n.d.	-
Hexabromobiphenyl	mg/kg		5	n.d.	-
Heptabromobiphenyl	mg/kg		5	n.d.	-
Octabromobiphenyl	mg/kg		5	n.d.	-
Nonabromobiphenyl	mg/kg		5	n.d.	-
Decabromobiphenyl	mg/kg		5	n.d.	-
Sum of PBDEs	mg/kg		-	n.d.	1000
Monobromodiphenyl ether	mg/kg		5	n.d.	-
Dibromodiphenyl ether	mg/kg		5	n.d.	-
Tribromodiphenyl ether	mg/kg		5	n.d.	-
Tetrabromodiphenyl ether	mg/kg		5	n.d.	-
Pentabromodiphenyl ether	mg/kg		5	n.d.	-
Hexabromodiphenyl ether	mg/kg		5	n.d.	-
Heptabromodiphenyl ether	mg/kg		5	n.d.	-
Octabromodiphenyl ether	mg/kg		5	n.d.	-
Nonabromodiphenyl ether	mg/kg		5	n.d.	-
Decabromodiphenyl ether	mg/kg		5	n.d.	-

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Test Item (s)	Unit	Method	MDL	Result No.1	Limit
DIBP (Di-isobutyl phthalate) (CAS No.: 84-69-5)	mg/kg	With reference to IEC 62321-8:2017. Analysis was performed by GC/MS.	50	n.d.	1000
DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	mg/kg	With reference to IEC 62321-8:2017. Analysis was performed by GC/MS.	50	n.d.	1000
BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	mg/kg	With reference to IEC 62321-8:2017. Analysis was performed by GC/MS.	50	n.d.	1000
DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	mg/kg	With reference to IEC 62321-8:2017. Analysis was performed by GC/MS.	50	n.d.	1000
DNOP (Di-n-octyl phthalate) (CAS No.: 117-84-0)	mg/kg	With reference to IEC 62321-8:2017. Analysis was performed by GC/MS.	50	n.d.	-
DINP (Di-isononyl phthalate) (CAS No.: 28553-12-0, 68515-48-0)	mg/kg	With reference to IEC 62321-8:2017. Analysis was performed by GC/MS.	50	n.d.	-
DIDP (Di-isodecyl phthalate) (CAS No.: 26761-40-0, 68515-49-1)	mg/kg	With reference to IEC 62321-8:2017. Analysis was performed by GC/MS.	50	n.d.	-
DNPP(Di-n-pentyl phthalate) (CAS No.: 131-18-0)	mg/kg	With reference to IEC 62321-8:2017. Analysis was performed by GC/MS.	50	n.d.	-
Antimony (Sb)	mg/kg	With reference to US EPA 3052: 1996. Analysis was performed by ICP-OES.	2	n.d.	-
Arsenic (As)	mg/kg		2	n.d.	-
Beryllium (Be)	mg/kg		2	n.d.	-
Halogen					
Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	With reference to BS EN 14582:2016. Analysis was performed by IC.	50	n.d.	-
Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg	With reference to BS EN 14582:2016. Analysis was performed by IC.	50	n.d.	-
Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg	With reference to BS EN 14582:2016. Analysis was performed by IC.	50	n.d.	-
Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg	With reference to BS EN 14582:2016. Analysis was performed by IC.	50	n.d.	-

Note：

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n.d. = Not Detected
3. MDL = Method Detection Limit
4. " - " = Not Regulated
5. The statement of compliance conformity is based on comparison of testing results and limits.
6. This test report supersedes the previous document bearing the report number KA/2020/60957, the report KA/2020/60957 was voided. The revised date is 2020/06/23.

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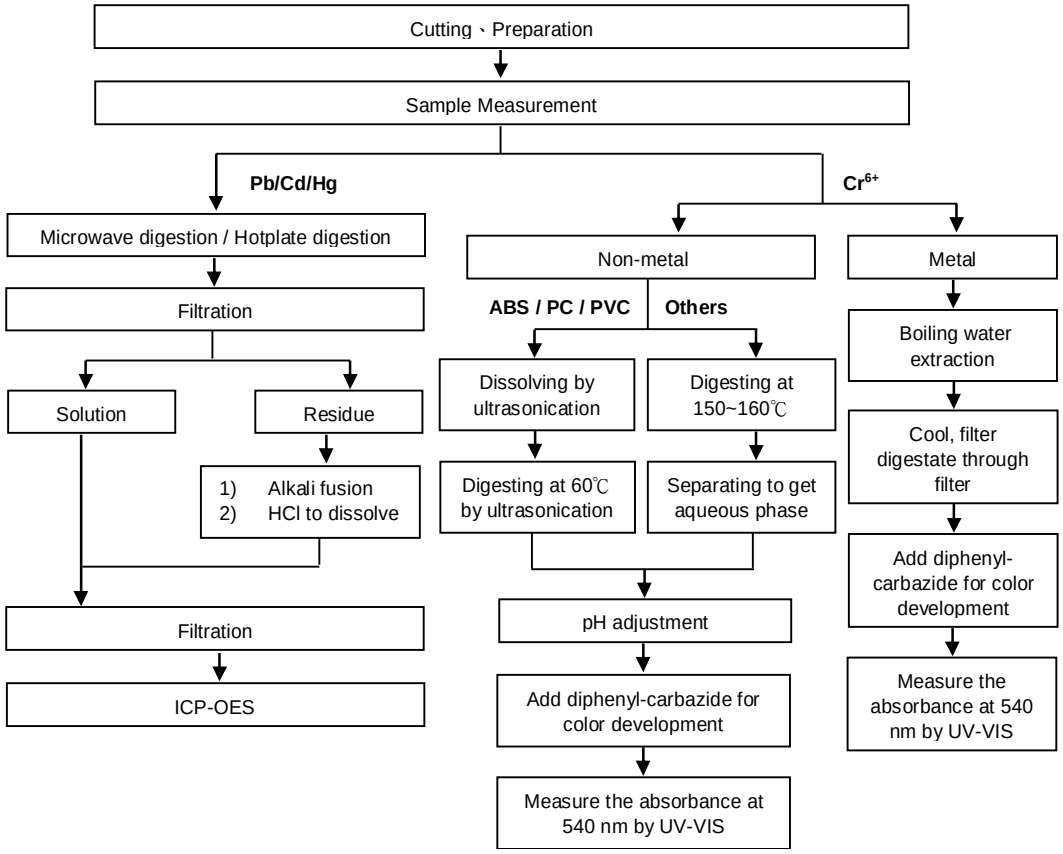
Analytical flow chart of Heavy Metal

These samples were dissolved totally by pre-conditioning method according to below flow chart.（Cr^{6+} test method excluded）



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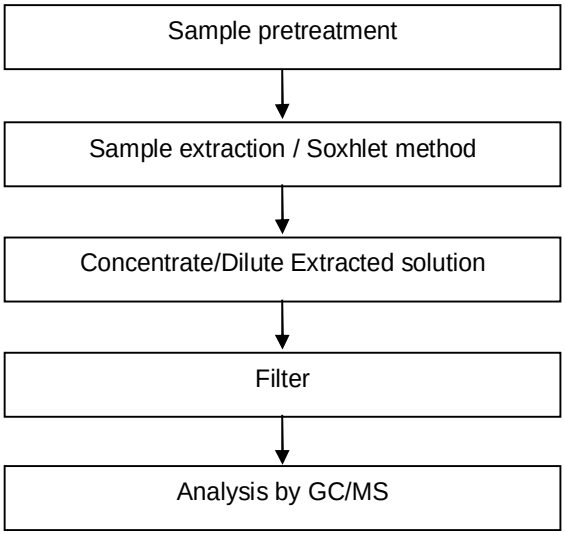
PBB/PBDE analytical FLOW CHART



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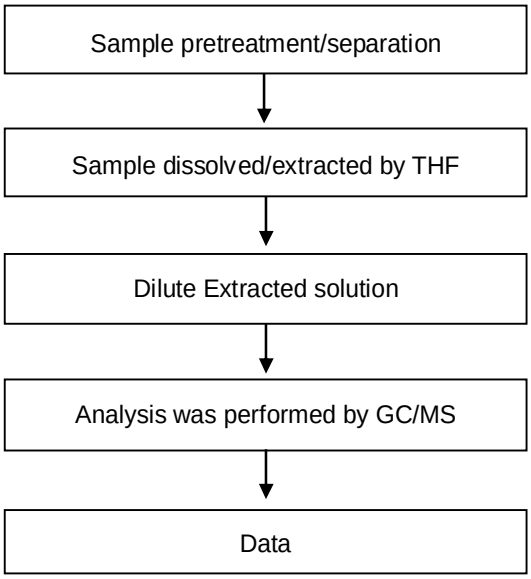
Analytical flow chart of phthalate content

【Test method: IEC 62321-8】



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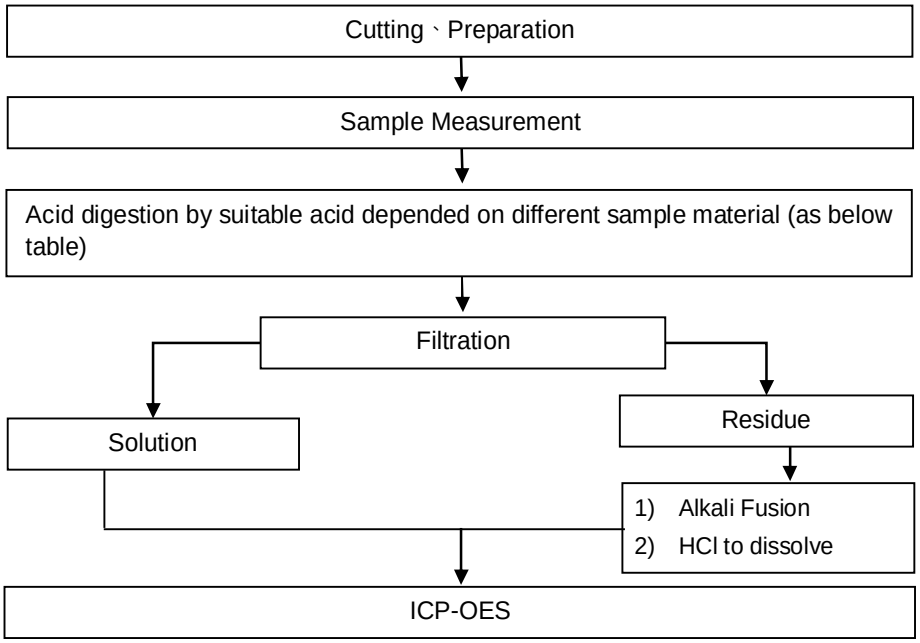
Flow Chart of digestion for the elements analysis performed by ICP-OES

These samples were dissolved totally by pre-conditioning method according to below flow chart.



Steel, copper, aluminum, solder	Aqua regia, HNO_3, HCl, HF, H_2O_2
Glass	HNO_3/HF
Gold, platinum, palladium, ceramic	Aqua regia
Silver	HNO_3
Plastic	H_2SO_4, H_2O_2, HNO_3, HCl
Others	Any acid to total digestion

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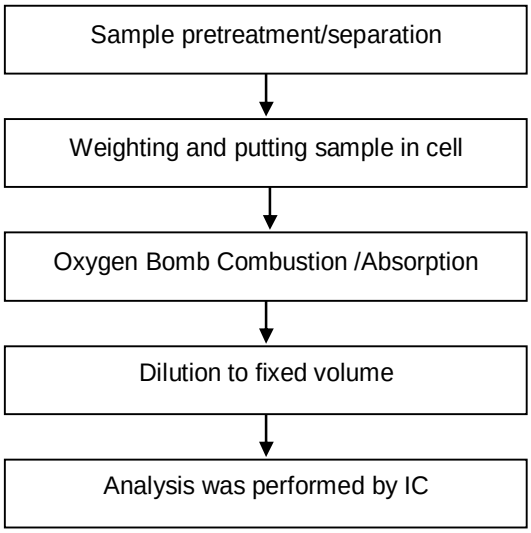
Analytical flow chart of Halogen



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*** The tested sample / part is marked by an arrow if it's shown on the photo. ***

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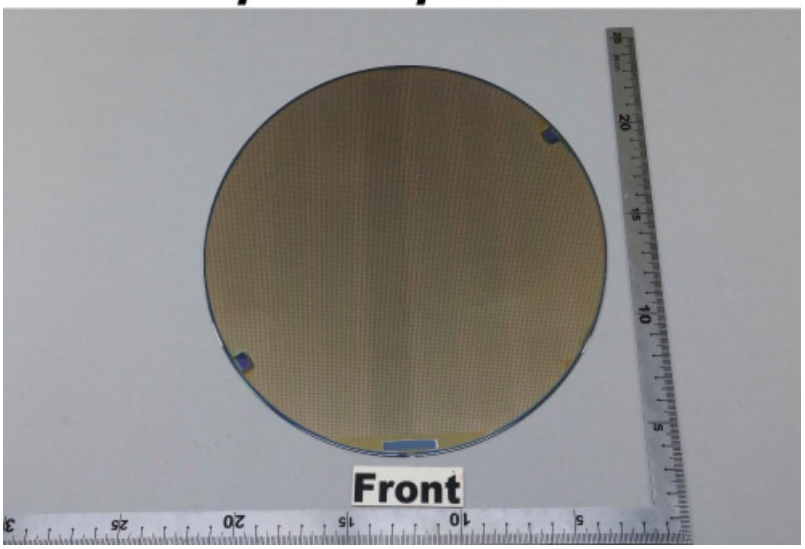

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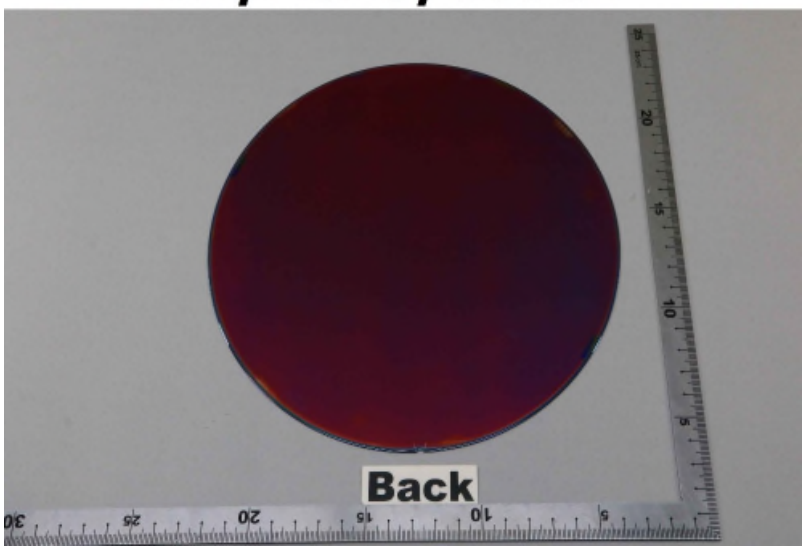

** End of Report **